Hydrogen Peroxide, 30% CMOS (Stabilized)





Material No.: 2190-23 Batch No.: 0000189547 Manufactured Date: 2017/12/08 Expiration Date: 2019/06/08

Certificate of Analysis

Test	Specification	Result
issay (H2O2)	30.0 - 32.0 %	31.6
Color (APHA)	<= 10	5
ree Acid (µeq/g)	<= 0.2	0.1
esidue after Evaporation	<= 10 ppm	2
mmonium (NH4)	<= 3 ppm	< 3
hloride (Cl)	<= 0.2 ppm	< 0.2
litrate (NO₃)	<= 2 ppm	< 1
hosphate (PO4)	<= 1 ppm	< 1
ulfate (SO4)	<= 3 ppm	< 3
race Impurities – Aluminum (Al)	<= 70.0 ppb	< 5.0
rsenic and Antimony (as As)	<= 10 ppb	< 10
race Impurities – Barium (Ba)	<= 20.0 ppb	< 1.0
race Impurities – Beryllium (Be)	<= 10.0 ppb	< 1.0
race Impurities – Bismuth (Bi)	<= 20.0 ppb	< 10.0
race Impurities – Boron (B)	<= 10.0 ppb	< 5.0
race Impurities – Cadmium (Cd)	<= 10.0 ppb	< 1.0
race Impurities – Calcium (Ca)	<= 50.0 ppb	< 1.0
race Impurities – Chromium (Cr)	<= 20.0 ppb	2.5
race Impurities – Cobalt (Co)	<= 10.0 ppb	< 1.0
race Impurities – Copper (Cu)	<= 10.0 ppb	< 1.0
race Impurities – Gallium (Ga)	<= 20.0 ppb	< 1.0
race Impurities – Germanium (Ge)	<= 10.0 ppb	< 10.0
race Impurities – Gold (Au)	<= 10.0 ppb	< 5.0
leavy Metals (as Pb)	<= 500 ppb	< 250

For questions on this Certificate of Analysis please contact Technical Services at 855.282.6867 or +1.610.573.2600 Avantor Performance Materials, LLC.

3477 Corporate Parkway. Center Valley, PA 18034. U.S.A. Phone: 610.573.2600 . Fax: 610.573.2610

Test	Specification	Result
Trace Impurities – Iron (Fe)	<= 50.0 ppb	2.6
Trace Impurities – Lead (Pb)	<= 10.0 ppb	< 10.0
Trace Impurities – Lithium (Li)	<= 10.0 ppb	< 1.0
Trace Impurities – Magnesium (Mg)	<= 10.0 ppb	< 1.0
Trace Impurities – Manganese (Mn)	<= 10.0 ppb	< 1.0
Trace Impurities – Molybdenum (Mo)	<= 10.0 ppb	< 5.0
Trace Impurities – Nickel (Ni)	<= 10.0 ppb	< 5.0
Trace Impurities – Niobium (Nb)	<= 10.0 ppb	< 1.0
Trace Impurities – Potassium (K)	<= 600.0 ppb	186.0
Trace Impurities – Silicon (Si)	<= 100.0 ppb	< 10.0
Trace Impurities – Silver (Ag)	<= 10.0 ppb	< 1.0
Trace Impurities – Sodium (Na)	<= 100.0 ppb	< 5.0
Trace Impurities – Strontium (Sr)	<= 10.0 ppb	< 1.0
Trace Impurities – Tantalum (Ta)	<= 10.0 ppb	< 5.0
Trace Impurities – Thallium (TI)	<= 50.0 ppb	< 5.0
Trace Impurities – Tin (Sn)	190.0 – 500.0 ppb	285.0
Trace Impurities – Titanium (Ti)	<= 10.0 ppb	< 1.0
Trace Impurities – Vanadium (V)	<= 10.0 ppb	< 1.0
Trace Impurities – Zinc (Zn)	<= 50.0 ppb	< 1.0
Trace Impurities – Zirconium (Zr)	<= 10.0 ppb	< 1.0
Particle Count – 0.5 µm and greater	<= 100 par/ml	53
Particle Count – 1.0 µm and greater	<= 10 par/ml	1

For Microelectronic Use

Country of Origin: US Packaging Site: Paris Mfg Ctr & DC



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